N-Channel Power MOSFET 600 V, 360 m Ω

Features

- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS ($T_J = 25$ °C unless otherwise noted)

Parameter			Symbol	NDD	Unit
Drain-to-Source Voltage			V _{DSS}	600	V
Gate-to-Source Volta	.ge		V _{GS}	±25	V
Continuous Drain	Steady State	T _C = 25°C	I _D	11	Α
Current R _{θJC}	State	T _C = 100°C		6.9	
Power Dissipation – R _{θJC}	Steady State T _C = 25°C		P _D	114	W
Pulsed Drain Current	t _p = 10 μs		I _{DM}	44	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)			IS	13	Α
Single Pulse Drain-to-Source Avalanche Energy (I _D = 3.5 A)			EAS	64	mJ
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 15)			V _{ISO}	-	V
Peak Diode Recovery (Note 1)			dv/dt	15	V/ns
Lead Temperature for Soldering Leads			T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. $I_{SD} \le 13$ A, $di/dt \le 400$ A/ μ s, $V_{DS\ peak} \le V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$

THERMAL RESISTANCE

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	1.1	°C/W
Junction-to-Ambient Steady State (Note 3) NDD60N360U1 (Note 2) NDD60N360U1-1 (Note 2) NDD60N360U1-35G	$R_{ hetaJA}$	47 98 95	°C/W

- 2. Insertion mounted
- Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces)

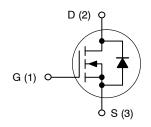


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V _{(BR)DSS}	R _{DS(ON)} MAX		
600 V	360 mΩ @ 10 V		

N-Channel MOSFET









MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 3 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

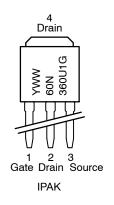
Characteristic	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		600			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	Reference to 25°C, I _D = 1 mA			560		mV/°C
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	T _J = 25°C			1	μΑ
			T _J = 125°C			100	1
Gate-to-Source Leakage Current	I _{GSS}	V _{GS} = ±25 V				±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250$	Αμ Ο	2	3.2	4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	Reference to 25°C, I _D =	: 250 μA		8.6		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 5.$	5 A		320	360	mΩ
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 5.	5 A		10		S
DYNAMIC CHARACTERISTICS							
Input Capacitance	C _{iss}				790		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f$	= 1 MHz		47		1
Reverse Transfer Capacitance	C _{rss}	30 0.0			3.0		1
Effective output capacitance, energy related (Note 6)	C _{o(er)}	V _{GS} = 0 V, V _{DS} = 0 to 480 V			38.9		-
Effective output capacitance, time related (Note 7)	C _{o(tr)}	I_D = constant, V_{GS} = 0 V, V_{DS} = 0 to 480 V			135		
Total Gate Charge	Q_g	V _{DS} = 300 V, I _D = 13 A, V _{GS} = 10 V			26		nC
Gate-to-Source Charge	Q_{gs}				4.7		1
Gate-to-Drain Charge	Q _{gd}				12.9		1
Plateau Voltage	V_{GP}				5.6		V
Gate Resistance	R_{g}				4.5		Ω
RESISTIVE SWITCHING CHARACTER	ISTICS (Note 5)					
Turn-on Delay Time	t _{d(on)}				10		ns
Rise Time	t _r	V _{DD} = 300 V, I _D = 1	3 A,		20		
Turn-off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, R_{G} = 0 \Omega$			26		
Fall Time	t _f				22		
SOURCE-DRAIN DIODE CHARACTER	RISTICS						
Diode Forward Voltage	V_{SD}	$I_S = 13 \text{ A}, V_{GS} = 0 \text{ V}$ $T_J = 25^{\circ}\text{C}$ $T_J = 100^{\circ}\text{C}$			0.93	1.6	V
					0.86		
Reverse Recovery Time	t _{rr}	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 13 \text{ A}, d_{i}/d_{t} = 100 \text{ A}/\mu\text{s}$			303		ns
Charge Time	ta				206		1
Discharge Time	t _b				97		
Reverse Recovery Charge	Q _{rr}				3.6		μС

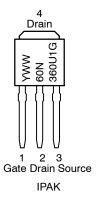
^{4.} Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.

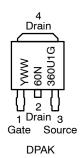
5. Switching characteristics are independent of operating junction temperatures.

6. $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$ 7. $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$ Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

MARKING DIAGRAMS







Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NDD60N360U1-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N360U1-35G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N360U1T4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL CHARACTERISTICS

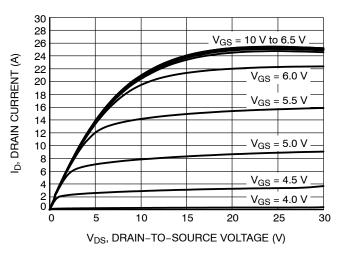


Figure 1. On-Region Characteristics

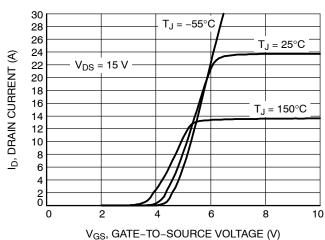


Figure 2. Transfer Characteristics

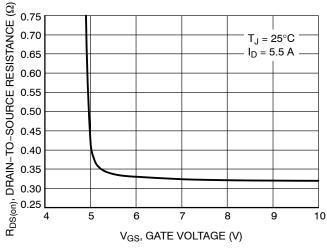


Figure 3. On-Resistance vs. Gate-to-Source Voltage

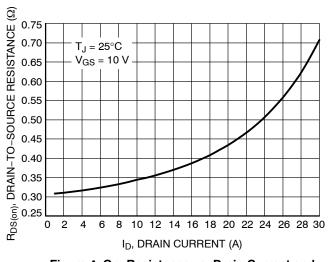


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

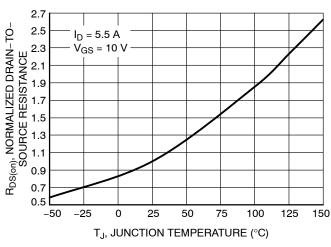


Figure 5. On–Resistance Variation with Temperature

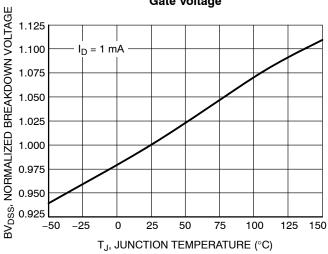


Figure 6. Breakdown Voltage Variation with Temperature

TYPICAL CHARACTERISTICS

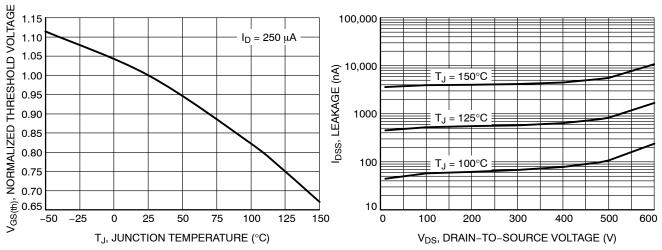


Figure 7. Threshold Voltage Variation with Temperature

Figure 8. Drain-to-Source Leakage Current vs. Voltage

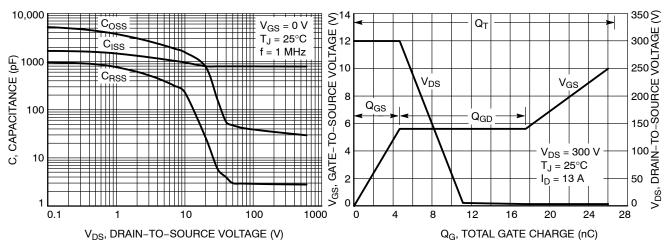


Figure 9. Capacitance Variation

Figure 10. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

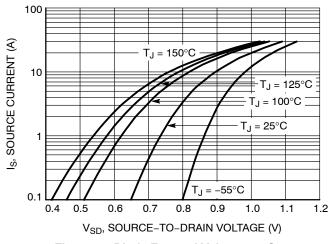


Figure 11. Diode Forward Voltage vs. Current

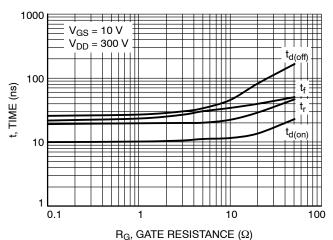


Figure 12. Resistive Switching Time Variation vs. Gate Resistance

TYPICAL CHARACTERISTICS

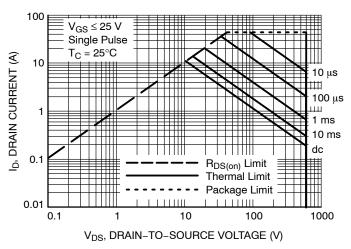


Figure 13. Maximum Rated Forward Biased Safe Operating Area NDD60N360U1

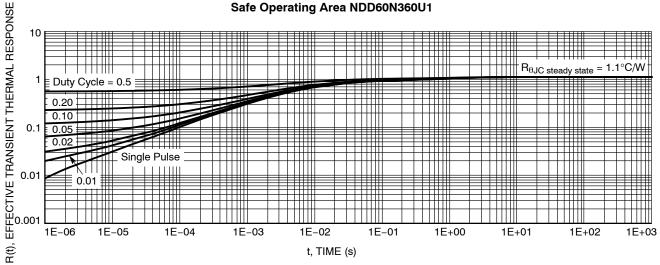
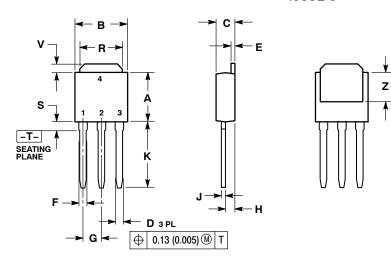


Figure 14. Thermal Impedance (Junction-to-Case) for NDD60N360U1

PACKAGE DIMENSIONS

IPAK CASE 369D-01 ISSUE C



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

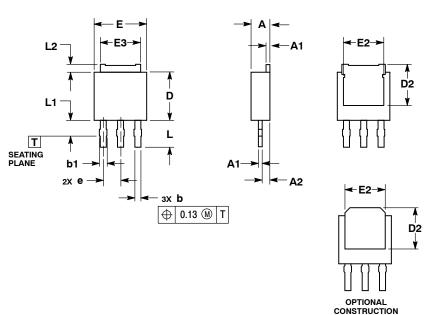
	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.35	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
Е	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.090	BSC	2.29 BSC		
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.350	0.380	8.89	9.65	
R	0.180	0.215	4.45	5.45	
S	0.025	0.040	0.63	1.01	
٧	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE

- 2. DRAIN 3. SOURCE 4. DRAIN

3.5 MM IPAK, STRAIGHT LEAD

CASE 369AD ISSUE B



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

 3. DIMENSION 6 APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS			
DIM	MIN	MAX		
Α	2.19	2.38		
A1	0.46	0.60		
A2	0.87	1.10		
b	0.69	0.89		
b1	0.77	1.10		
D	5.97	6.22		
D2	4.80			
E	6.35	6.73		
E2	4.57	5.45		
E3	4.45	5.46		
е	2.28 BSC			
L	3.40	3.60		
L1		2.10		
L2	0.89	1.27		

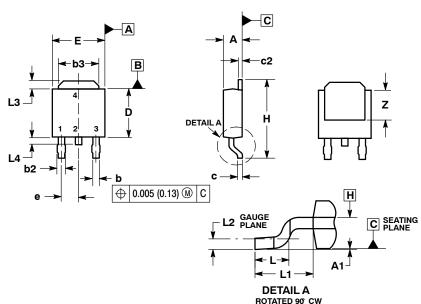
STYLE 2:

- PIN 1. GATE 2. DRAIN
 - SOURCE
 - 4. DRAIN

PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE)

CASE 369C-01 ISSUE D



- DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
 CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- MENSIONS b3, L3 and Z. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
 5. DIMENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.
 6. DATUMS A AND B ARE DETERMINED AT DATUM

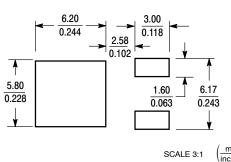
	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108 REF		2.74 REF	
L2	0.020 BSC		0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

STYLE 2:

PIN 1. GATE 2. DRAIN

- 3. SOURCE 4. DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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